

Fitting Models to Data

Inverting Data

- Start w/ well-posed FD/FE model

$$[K]\{u\} = \{6\}$$

(i.e. $[K]^{-1}$ exists)

- measure some u_i with uncertainty
- deduce $\{b\}$ through LS fit to data
- estimate complete $\{u\}$ from model for estimated $\{b\}$
- estimate inverse noise in $\{u\}$ and system noise in $\{b\}$
- examine misfit between data and model

To do this, need prior estimates of $\text{Cov}(u)$, $\text{Cov}(b)$ and expected data-model misfit

Data-Model Mismatch

$$\{d\} = [S]\{u\} + \{s\}$$


↑ data ↑ sampling matrix (e.g. point average derivative etc.) ↑ model output ← misfit (2 pieces) → measurement error, modeling error (difference between reality and model)

- In FE case, sampling matrix, $[S]$, is determined from basis functions

e.g. given true u at point $(x, y, z)_k$, then

$$\text{FE sol'n there is } u(x, y, z)_k = \sum_j u_j \phi_j(x, y, z)_k$$

$$\therefore S_{kj} = \phi_j(x, y, z)_k \text{ for row index } k. \\ \text{Column index } j$$

e.g.  only 3 non-zero basis, i.e. j 's \Rightarrow sparse

- Common to "de-mean" everything, i.e.

$$\left. \begin{aligned} \{u\} &= \{\bar{u}\} + \{\tilde{u}\} \\ \{b\} &= \{\bar{b}\} + \{\tilde{b}\} \\ \{d\} &= \{\bar{d}\} + \{\tilde{d}\} \end{aligned} \right\} \begin{aligned} &\text{a "mean" value +} \\ &\text{perturbation} \\ &\text{Sometimes called} \\ &\text{Best prior estimate, BPE} \end{aligned}$$

$$\text{such that } \begin{aligned} \{\bar{u}\} &= [K]^{-1} \{\bar{b}\} \\ \{\bar{d}\} &= [S] \{\bar{u}\} \end{aligned} \quad \begin{aligned} &\dots \text{perturbations are} \\ &\text{the unknowns} \\ &\text{BPE is known} \end{aligned}$$

$$\text{and then } \begin{aligned} \{\tilde{u}\} &= [K]^{-1} \{\tilde{b}\} \\ \{\tilde{d}\} &= [S] \{\tilde{u}\} + \{\tilde{d}\} \end{aligned}$$

Drop "~" over top for convenience, but are only working w/ perturbations now

then $\{d\} = \{d\} - \underbrace{[S][K^{-1}]\{b\}}_{\{x\}}$

- want to find $\{b\}$ such that $\{d\} \approx 0$

i.e. $[S][K^{-1}]\{b\} \approx \{d\}$

Not square, no inverse, solve in LS sense

i.e. $[S][K^{-1}]\{b\} = \{d\}$

- Normal Egn's (minimum variance misfit sol'n)

$$[S][K^{-1}]^T [S][K^{-1}]\{b\} = [S][K^{-1}]^T \{d\}$$

$$\{b\} = \underbrace{[S][K^{-1}]^T [S][K^{-1}]}_{[B]} [S][K^{-1}]^T \{d\}$$

• So $\{b\}$ is linear in $\{d\}$ i.e. $\{b\} = [B]\{d\}$

i.e. estimate for $\{b\}$ is linear in the data

• Can get $\{u\}$ from estimated $\{b\}$ as

$$\{u\} = [K^{-1}][B]\{d\}$$

• given data w/ noise, then

$$[\text{Cov}(b)] = [B][\text{Cov}(d)][B]^T$$

$$[\text{Cov}(u)] = [K^{-1}][\text{Cov}(b)][K^{-T}]$$

• Different Sol'n strategies lead to different linear estimators $[B]$

e.g. what about SVD?

$$[S][K^{-1}]\{b\} = \{d\}$$

$$\{b\} = [V][\text{diag } 1/w][U]^T\{d\}$$

where $[S][K^{-1}] = [U][\text{diag } w][V^T]$ $[B]_{\text{SVD}}$

or $[B]_{\text{WLS}} = \dots$

or $[B]_{\text{GLS}} = \dots$

Aside: Normal Egn's for OLS same as SVD
(i.e. are minimum residual variance sol'n
to $[A]\{x\} = \{b\}$ where $m > n$)

Normal Egn's for $[A]\{x\} = \{b\}$

$$[A^T A]\{x\} = [A^T]\{b\}$$

SVD:

$$[A] = [U][\text{diag } w][V^T]$$

$$[A^T] = [V][\text{diag } w][U^T]$$

$$\underbrace{[V][\text{diag } w][U^T]}_{[A^T]} \underbrace{[U][\text{diag } w][V^T]}_{[A]}\{x\} = [V][\text{diag } w][U^T]\{b\}$$

$$\rightarrow [V][\text{diag } w^2][V^T]\{x\} = [V][\text{diag } w][U^T]\{b\}$$

multiply through by $[V^T]$; (recall $[V^T][V] = [I] = [V][V^T]$)

$$[\text{diag } w^2][V^T]\{x\} = [\text{diag } w][U^T]\{b\}$$

$$\rightarrow [V^T]\{x\} = [\text{diag } 1/w][U^T]\{b\}$$

multiply through by $[V]$

$$\{x\} = [V][\text{diag } 1/w][U^T]\{b\}$$

Exactly the SVD sol'n
to $[A]\{x\} = \{b\}$

- Can consider $\{s\}$ as having two sources of uncertainty

1. Model "mismatch" with nature

$$\text{i.e. } \underbrace{\{u\}}_{\text{Model Sol'n}} = \underbrace{\{u_{TR}\}}_{\text{"Truth"}} + \underbrace{\{\epsilon_m\}}_{\text{model error}}$$

2. data uncertainty (measurement noise)

$$\text{i.e. } \underbrace{\{d\}}_{\text{data}} = \underbrace{[S]\{u_{TR}\}}_{\text{Sampled "Truth"}} + \underbrace{\{\epsilon_d\}}_{\text{measurement error (noise)}}$$

then $\{s\} = \{d\} - [S]\{u\}$

$$= \{d\} - [S](\{u_{TR}\} + \{\epsilon_m\})$$

$$= \underbrace{\{\epsilon_d\}}_{\text{error due to measurement}} - \underbrace{[S]\{\epsilon_m\}}_{\text{error due to model imperfections}}$$

- misfit is superposition of these two error contributions